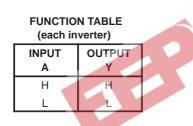
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- Flow-Through Architecture Optimizes **PCB** Layout
- Center-Pin V<sub>CC</sub> and GND Configurations **Minimize High-Speed Switching Noise**
- EPIC<sup>TM</sup> (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

### description

These devices contain six independent noninverters. They perform the Boolean function Y = A.

The 54AC11034 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74AC11034 is characterized for operation from -40°C to 85°C.

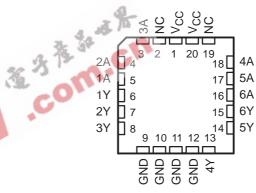


#### 20 🛛 1A 1Y 19 2A 2Y 🛛 2 18 3A 3Y [ 3 17 NC GND 4 GND 5 16 VCC GND 6 15 Vcc GND 17 14 NC 4Y 🛛 8 13 **4**A 12 5A 5Y **1**9 11 6A 10 6Y

54AC11034 ... J PACKAGE 74AC11034 ... DW OR N PACKAGE

(TOP VIEW)





NC - No internal connection

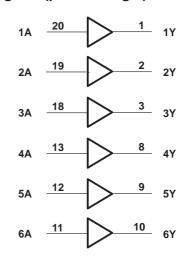
### logic symbol<sup>†</sup>

1 A	20	1	1	1Y
1A	19		2	2Y
2A 2A	18		3	21 3Y
2A 3A 4A 5A	18 13		8	4Y
50	12		9	5Y
6A	11		10	6Y

<sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DW, J, and N packages.

logic diagram (positive logic)



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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input voltage range, VI (see Note 1)	$\dots \dots \dots \dots \dots -0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V <sub>O</sub> (see Note 1)	–0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0 or V <sub>I</sub> > V <sub>CC</sub> )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Storage temperature range	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

#### recommended operating conditions

			54AC11034		74	'4AC11034		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		3	5	5.5	3	5	5.5	V
		V <sub>CC</sub> = 3 V	2.1	-		2.1			
VIH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15	G		3.15			V
		V <sub>CC</sub> = 5.5 V	3.85			3.85			
VIL		$V_{CC} = 3 V$			0.9			0.9	
	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35			1.35	V
		V <sub>CC</sub> = 5.5 V			1.65			1.65	
VI	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		$V_{CC} = 3 V$			-4			-4	
ЮН	High-level output current	$V_{CC} = 4.5 V$			-24			-24	mA
		V <sub>CC</sub> = 5.5 V			-24			-24	
		$V_{CC} = 3 V$			12			12	
IOL	Low-level output current	$V_{CC} = 4.5 V$			24			24	mA
		V <sub>CC</sub> = 5.5 V			24			24	
$\Delta t/\Delta v$	Input transition rise or fall rate		0		10	0		10	ns/V
TA	Operating free-air temperature		-55		125	-40		85	°C



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	TEST CONDITIONS	N	T,	ן = 25°C	;	54AC1	1034	74AC1	1034	UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
		3 V	2.9			2.9		2.9		
	I <sub>OH</sub> = – 50 μA	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
Vou	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.4		2.48		v
VOH		4.5 V	3.94			3.7		3.8		
	I <sub>OH</sub> = – 24 mA	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
		3 V			0.1		0.1		0.1	
	I <sub>OL</sub> = 50 μA	4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
Ve	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44	V
VOL	lat = 24  mA	4.5 V			0.36		0.5		0.44	v
	I <sub>OL</sub> = 24 mA	5.5 V	3		0.36		0.5		0.44	
	I <sub>OL</sub> = 50 mA <sup>†</sup>	5.5 V	23		0		1.65			
	I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V	50.	-					1.65	
lj	VI = V <sub>CC</sub> or GND	<b>5.5</b> ∨	-	3.	±0.1		±1		±1	μΑ
ICC	$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V	0		4		80		40	μA
Ci	$V_{I} = V_{CC}$ or GND	5 V		3.5						pF

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Т	Δ = 25°C	;	54AC1	1034	74AC1	1034	UNIT
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
<sup>t</sup> PLH	A	V	1.5	5.7	9.1	1.5	10.7	1.5	10.1	20
<sup>t</sup> PHL		I	1.5	5.5	8.3	1.5	9.9	1.5	9.2	ns

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

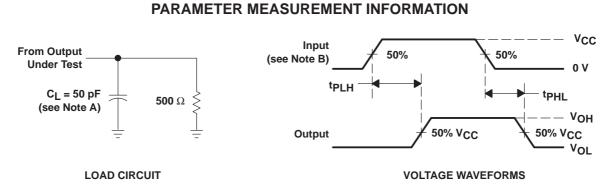
PARAMETER	FROM	то	Т	₄ = 25°C	;	54AC1	1034	74AC1	1034	UNIT
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
<sup>t</sup> PLH	A	V	1.5	4	6.3	1.5	7.4	1.5	6.9	20
<sup>t</sup> PHL		ſ	1.5	4	6.2	1.5	7.3	1.5	6.8	ns

# operating characteristics, $V_{CC} = 5 V$ , $T_A = 25^{\circ}C$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub> Power dissipation capacitance per gate	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	27	pF



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NOTES: A. CL includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ , t<sub>r</sub> = 3 ns, t<sub>f</sub> = 3 ns.
- C. The outputs are measured one at a time with one input transition per measurement.

#### Figure 1. Load Circuit and Voltage Waveforms





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